

VXI Digital Test Solutions

High Performance TTL

VXI Digital Test Modules

3 Models

SR192/64TS

SR192/96TS

SR192/TS

Talon Instruments is offering it's popular SR192 VXI Digital Test Module in standard pre-configured models at significant savings.

If your digital test requirements include TTL logic levels, "at speed" testing and deep vector memory Talon has a low cost VXI digital system for you.

The new low cost pre-configured models are capable of performing stimulus/response, parallel and serial bus emulation test functions. These models include features such as:

- Timing Rates to 50MHz
- Data Rates to 25MHz, (50MHz Multiplexed)
- TTL voltage levels
- 50mA Source/Sink
- 5 Memory Architecture (Stimulus, Tristate, Record, Expect & Mask)
- 128K Bits Memory/Channel, (256K Multiplexed)
- Real-Time error capture
- Parallel and Serial bus emulation
- Data Formats (Hold,RTZ,RT0, & RTC)
- Conditional/Unconditional Jump, Go-sub Test Sequences
- 128K Test Sequence Memory
- VXI Plug&play Drivers
- Active X Graphic Software Development Routines

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INSTRUMENTS

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Model Descriptions

The three High Performance TTL VXI models offered in standard configurations are housed in the SR192 motherboard which is a 2-slot "C" size VXI module. The SR101 timing generator(s) are utilized and the I/O modules are the SR115 bi-directional 16 channel modules. Each system includes the SR210 Accessory Module which provides a clock source programmable from 100Hz to 50MHz for internal timing and external devices. The SR192/20 Development Environment software package for creating and editing test programs is also included with each model. Models SR192/64TS and SR192/96TS may be field upgraded at a later date with a second timing generator and additional I/O modules.

- **SR192/64TS** provides 64 bidirectional channels of TTL voltage level digital stimulus/response and a single timing generator.
- **SR192/96TS** provides 96 bidirectional channels of TTL voltage level digital stimulus/response and a single timing generator.
- **SR192/TS** provides 192 bidirectional channels of TTL voltage level stimulus/response and 2 timing generators. The 192 channels may be programmed as a single test system or two fully independent 96 channel systems.

SR115 Digital I/O Module

The SR115 is a 16 channel I/O module designed to be installed as 1 of 12 daughter boards in a Model SR192 VXI Digital Test Module. The following specifications apply:

General

16 Bi-directional I/O Channels
128K Bits per channel (256K Multiplex Mode)
25MHz data rate (50MHz Multiplex Mode)
Parallel and Serial Operating Modes
Data Formats (Hold, RTZ, RT0, & RTC)
<3ns skew

Electrical

Output

High Level min 2.4V
Low Level max 0.4V
Source Current 50mA
Sink Current 50mA
Output Impedance 50Ω
Short Circuit Protected

Input

High Threshold 2.0V
Low Threshold 0.8V
Input Impedance >10KΩ

SR210 Clock Source

The SR210 is installed in its own daughter board slot and provides internal and external clock sources.

Specifications

Internal 2
External 3
Range 100Hz to 50MHz
Resolution 0.029 Hz
Output Levels 2@TTL
1@ +8 to -8 V

SR101 Timing Generator

One or two SR101 timing generators may be installed in an SR192 motherboard. Each SR101 will control up to 6 I/O modules.

The function of the SR101 timing generator is to provide the timing and control for the SR192 when executing a test or emulating a bus interface. The SR101 generates timing signals to the UUT, tests signals from the UUT, generates the required memory address and control signals for the I/O modules, and samples the results from the I/O modules.

Specifications

Clocks

Internal	1
External	2 Front Panel
Maximum Frequency	50MHz
External Input Levels	TTL
External Input Impedance	82Ω to ground

Output Signals

TSOUT1-5	Qty. 5
Minimum Period	20 nsec
Output Levels	TTL
Output Impedance	<50Ω

Input Signals

TSINP1-2	Qty. 2
Input Levels	TTL
Input Impedance	82Ω to ground

Test Sequencing

Test Sequence Memory	128K
Conditional & Unconditional	Jump, Go-sub
Looping	32K

SR192/20

The Development Environment is an Active X editor used to generate and edit table data, timing data and create test sequences. It is an interactive 32bit Windows application which aids the test engineer in generating and testing his test programs. It shortens the test development time significantly and is compatible with most test languages.